

**Amendments to the Specification:**

Please replace paragraph [0005] beginning at line 1 on page 2, with the following amended paragraph:

[0005] This application incorporates by reference herein in its entirety, the commonly-owned and concurrently filed U.S. Application No. ~~[UNKNOWN]~~, Attorney Docket ~~BOX016-US~~, Client Docket ~~AMAT-008546USA~~ 10/813,407 entitled "High Throughput Measurement Of Via Defects In Interconnects" filed by Jiping Li et al.

Please replace the paragraph [0044] at page 14, with the following amended paragraph:

[0044] Therefore, the duration  $\Delta t$  (~~between times  $t_1$  and  $t_6$  in FIG. 1E~~) times  $t_2$  and  $t_6$  in FIG. 1D) is selected to be sufficiently small to ensure that a temperature rise due to presence of heat from beam 111 is noticeable in the hot image. In some embodiments, duration  $\Delta t$  is selected to be the time at which the temperature after time  $t_2$  falls to  $(1/e)$  of the steady state value during period  $t_1$ - $t_2$ . In other embodiments, duration  $\Delta t$  is selected experimentally, after trial and error with different durations, to find subsurface defects as described next. In some embodiments, duration  $\Delta t$  is on the order of a few microseconds (e.g. 2-3 microseconds).